

<b>Notice of References Cited</b>	Application/Control No. 10/644,937	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner William C. Doerrler	Art Unit 3744	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,122,899	03-1964	COSTANTINI ANTHONY R; et. al.	62/419
	B	US-3,178,902	04-1965	COSTANTINI ANTHONY R; et. al.	62/237
	C	US-3,353,314	11-1967	MELCHER GEORGE W	52/127.9
	D	US-3,712,078	01-1973	Maynard et al.	62/448
	E	US-4,776,182	10-1988	Gidseg, Edward D.	62/448
	F	US-5,212,924	05-1993	Finkelstein, Burl	52/582.2
	G	US-5,284,023	02-1994	Silva et al.	62/77
	H	US-6,070,424	06-2000	Bauman et al.	62/279
	I	US-6,122,879	09-2000	Montes, Mario	52/592.1
	J	US-6,216,410	04-2001	Haberman, Kurt Evan	52/591.1
	K	US-2002/0093276	07-2002	Kawakami, Takeshi	312/405
	L	US-6,735,976	05-2004	Lee, Jae-Seung	62/419
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP1174666	01-2002	EPO	Watanabe	---
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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